

<b>Notice of References Cited</b>	Application/Control No. 09/988,107	Applicant(s)/Patent Under Reexamination HACHISU ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,603,528	08-2003	Tanaka et al	349/156
	B	US-			
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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